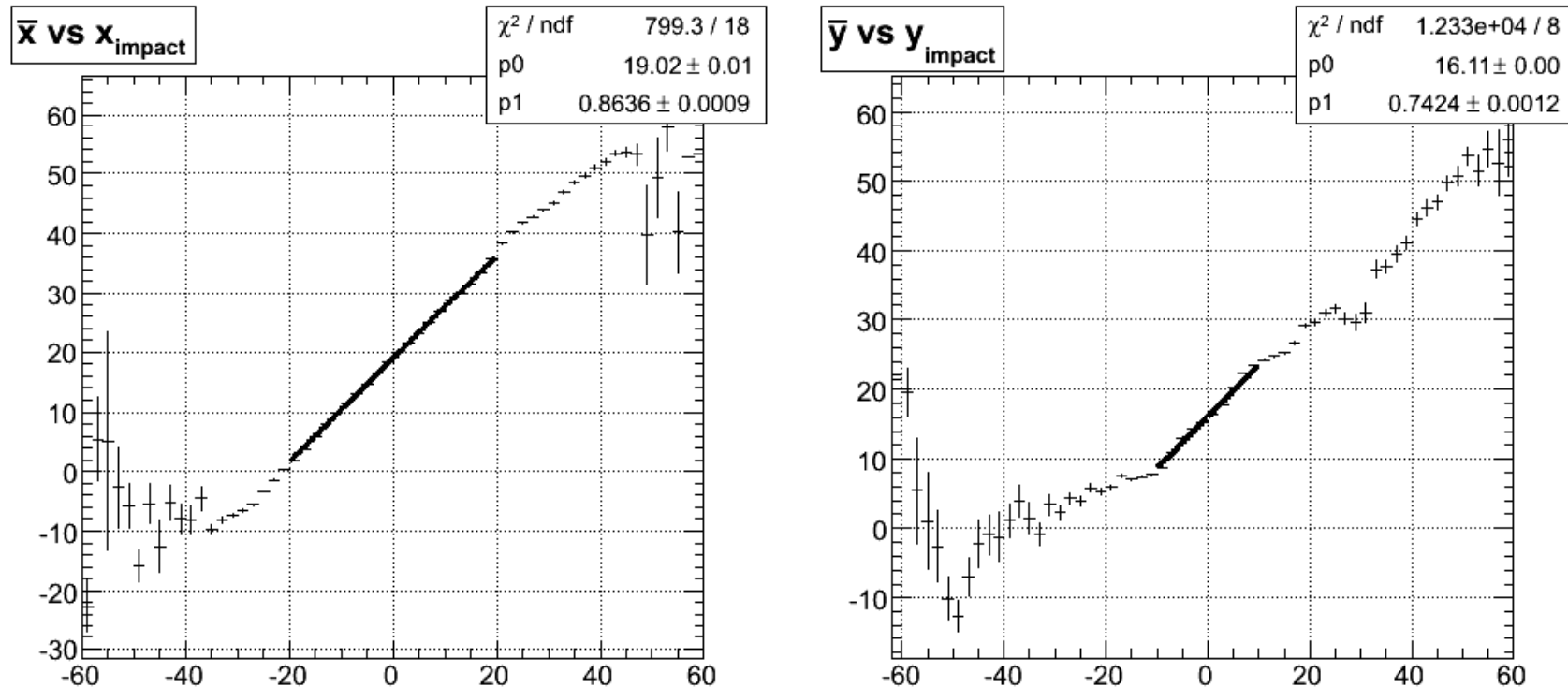


ECAL alignment update

David Ward

- ❖ A few thoughts about ECAL alignment
- ❖ And related issue of the drift velocity of the tracking
- ❖ Reminder of what was shown in last meeting...
- ❖ and follow up on ideas shown on 9 February

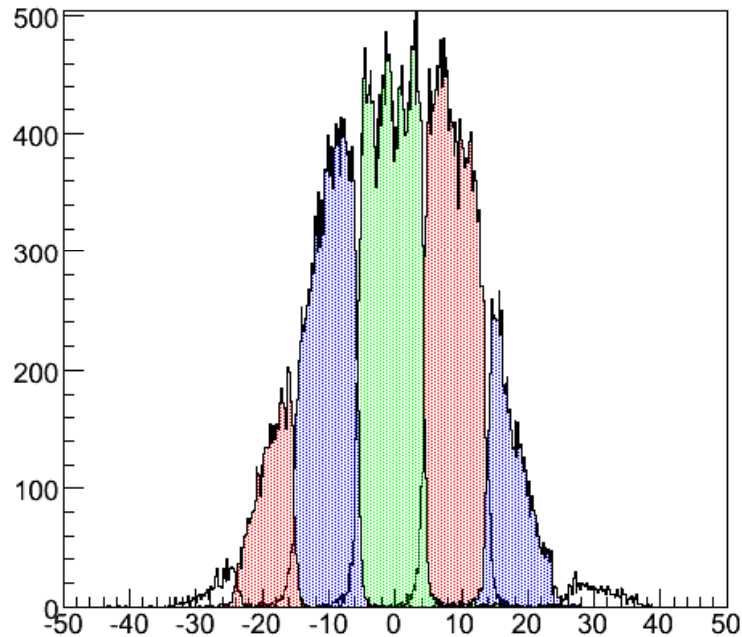
2006 approach



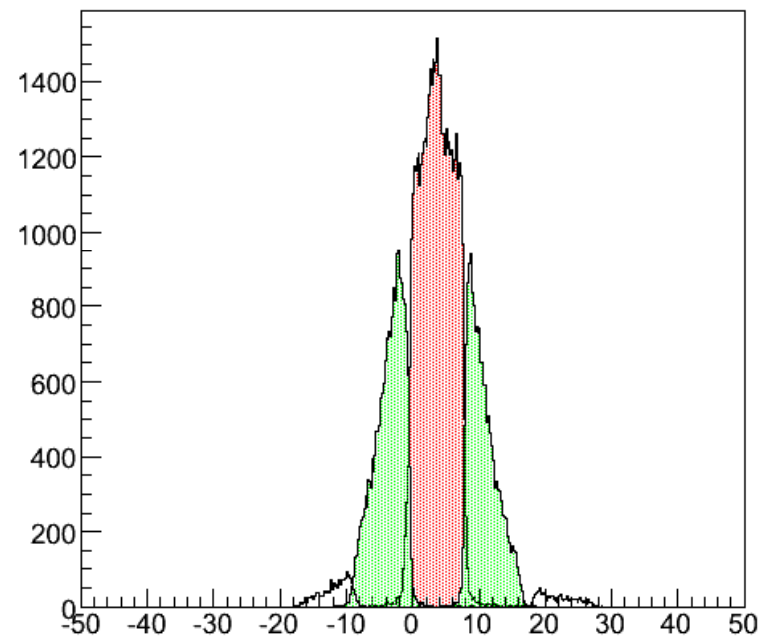
- Apply to 2007 data (run 300428; 50 GeV e⁻)
- Intercept at x(track)=0 gives ECAL offset
- Gradient gives correction to drift velocity (assuming 1cm pitch of ECAL is accurate)
- But shape in y is not simply linear, so procedure unreliable?

Track position vs pad index in layer 1

x track Ecal hit : $6*(WI-1)+I= 11$



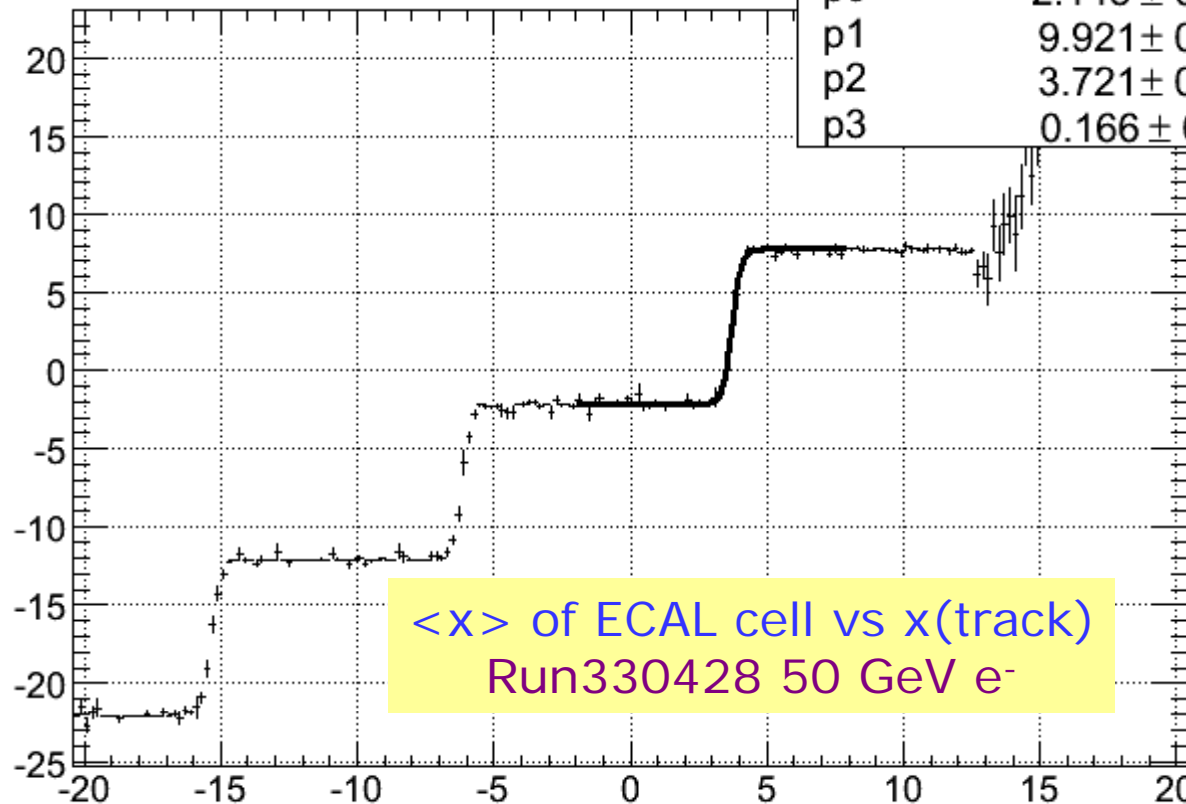
y track Ecal hit : $6*(WJ-1)+J= 11$



- Consider events with just a single hit in first layer
- For each cell index in x (or y) plot x (y) of extrapolated track
- Identify coordinates of cell edges
- Plots shown for Run331298 (30 GeV π^+)

Fit Fermi function to extract parameters

x(layer 1) vs x_{impact}

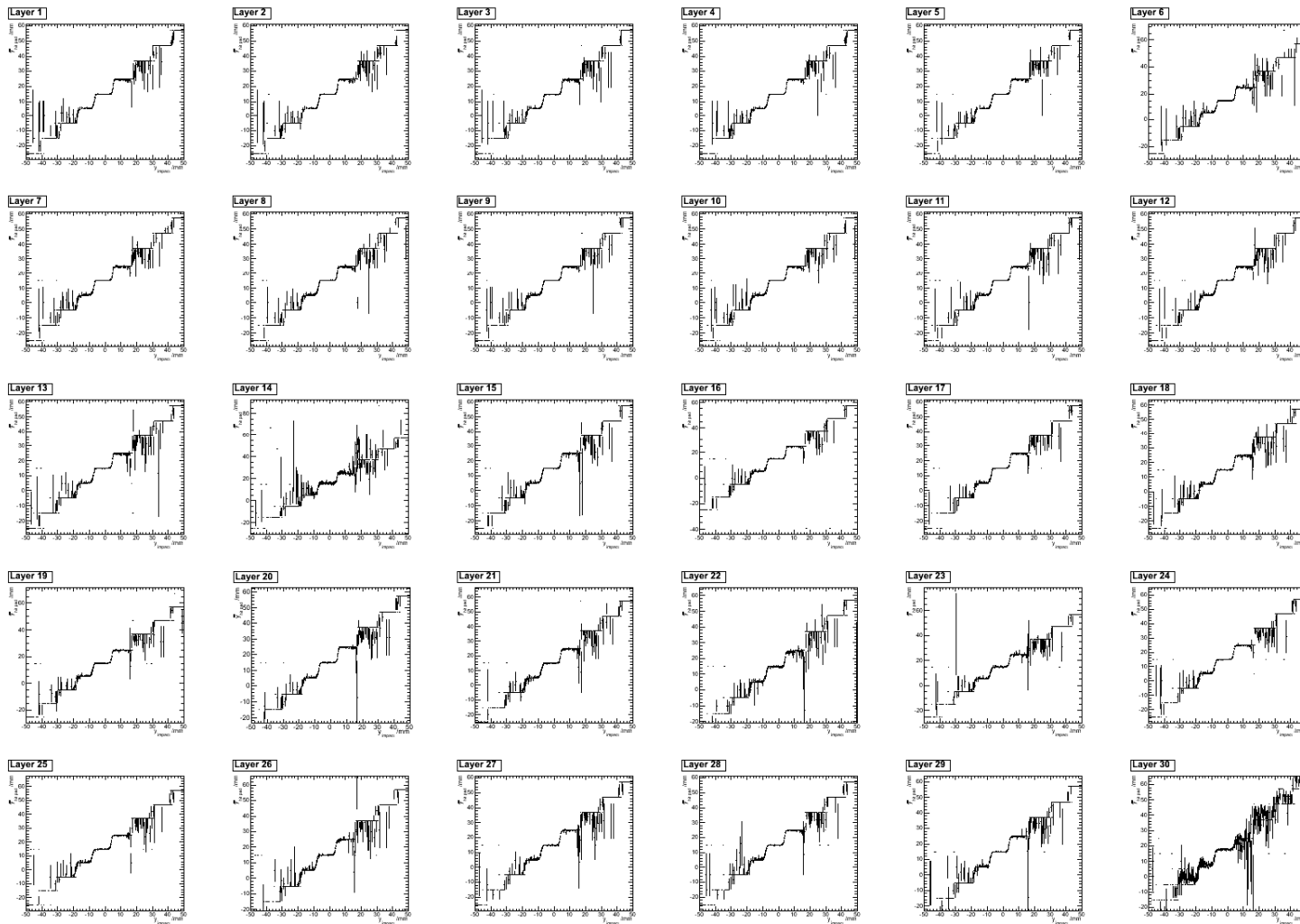


Cell width
Edge position

Potential to fix edges to a few tens of microns?

Run 330436 – select non-interacting π^-

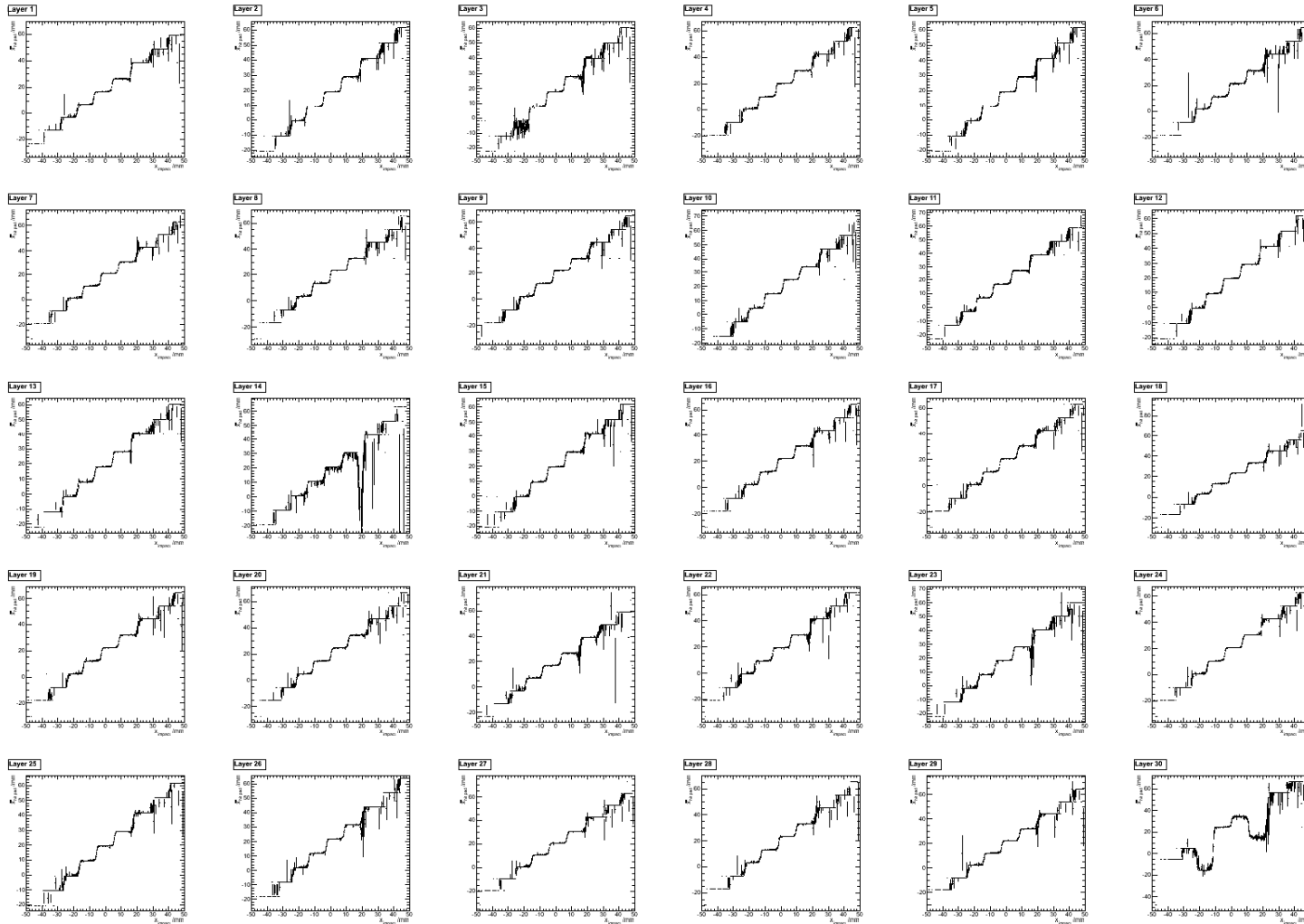
y



- All 30 layers shown.
- Could use more statistics.
- But \exists one pad with both edges clear.

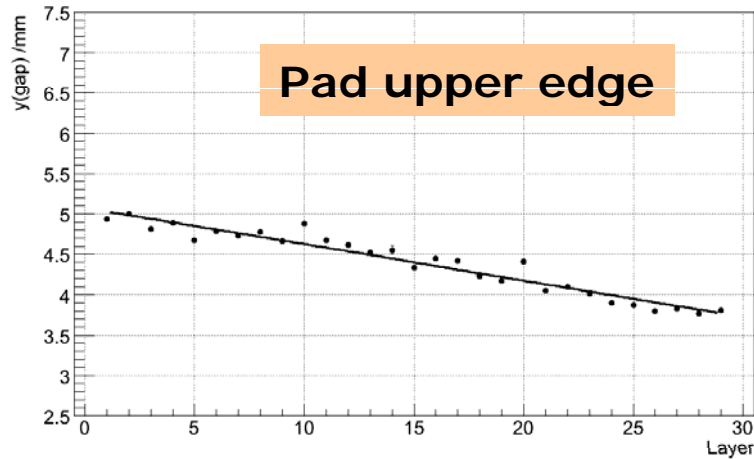
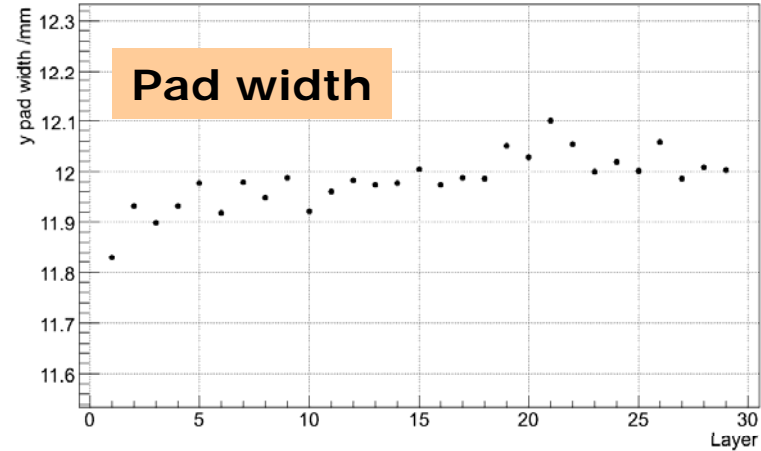
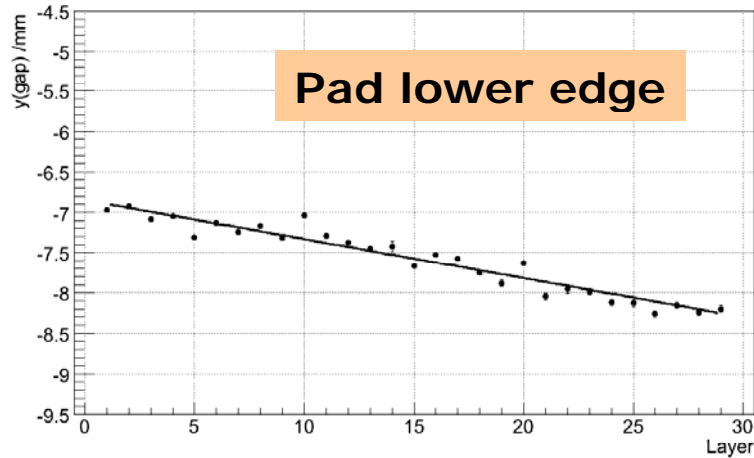
Run 330436 – select non-interacting π^-

X



Layer 30
Mapping
error?

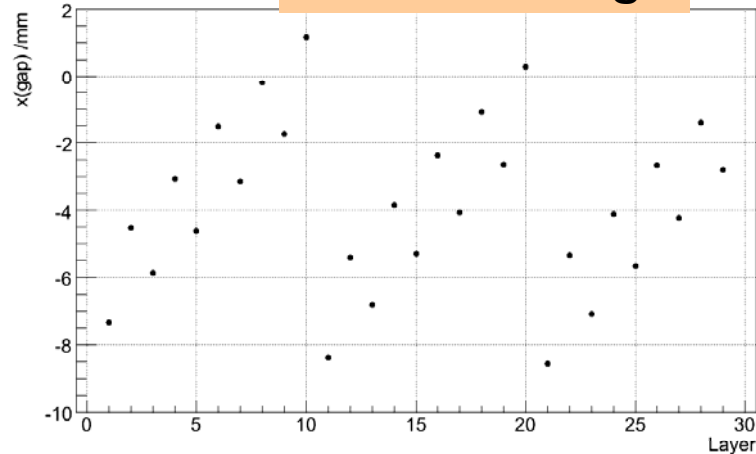
Measure "cell width" in y



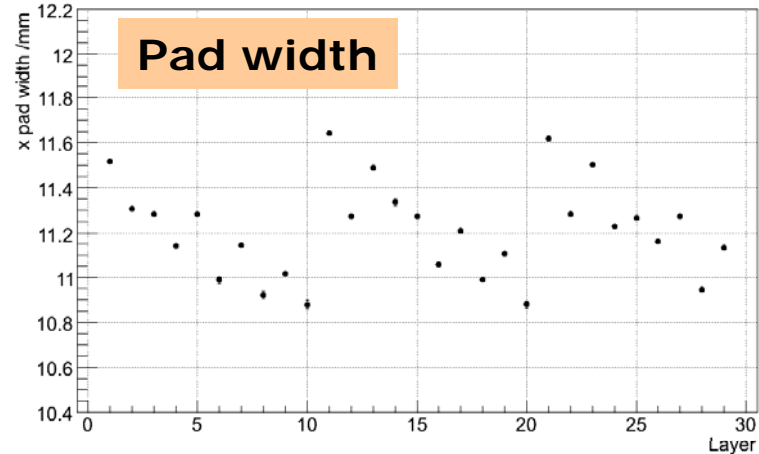
- Tilt of ECAL w.r.t. beam coordinates clearly discernible. ~ 6 mrad.
- Apparent pad width is reasonably constant to $\pm 1\%$, though possibly some structure.
- i.e. drift velocity correction in y should be $\sim 1.20 \pm 0.01$.

Likewise measure "cell width" in x

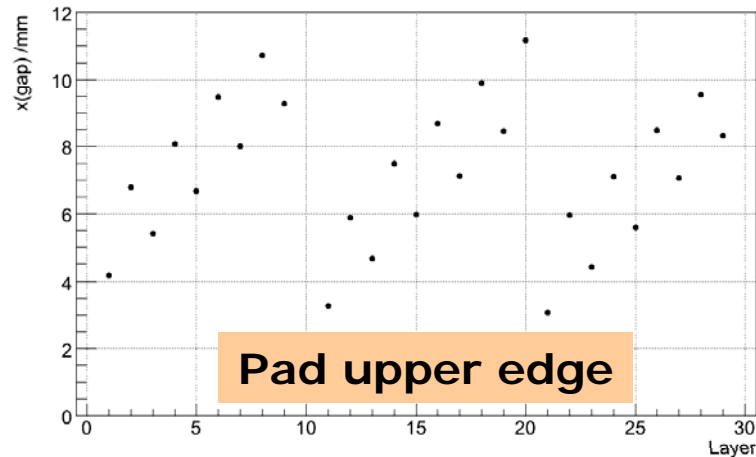
Pad lower edge



Pad width

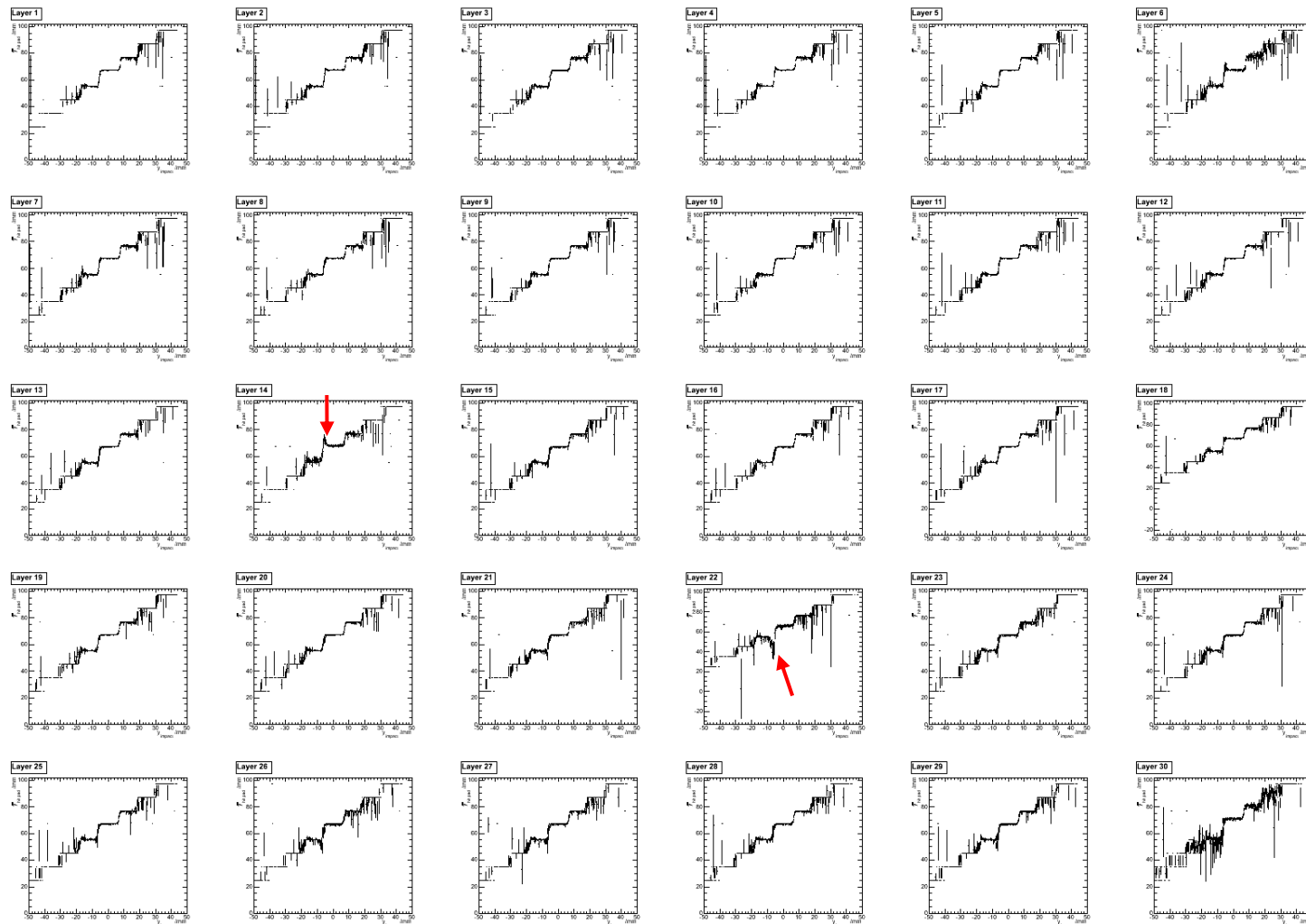


Pad upper edge



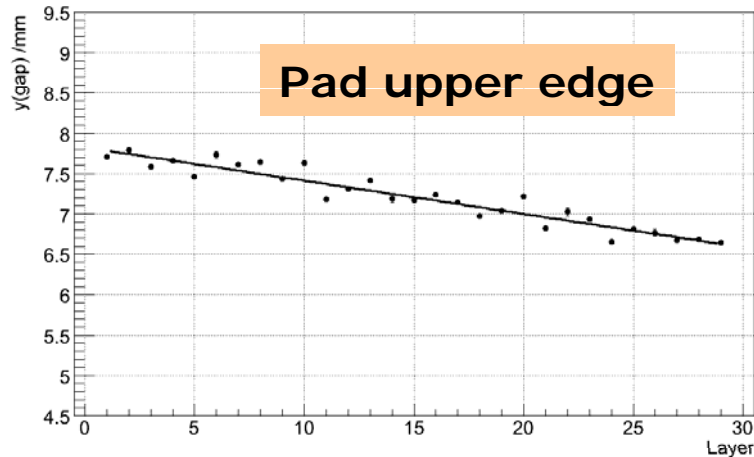
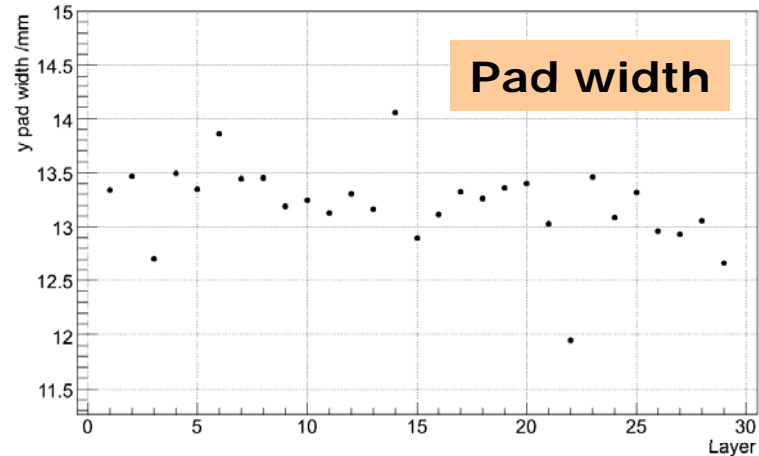
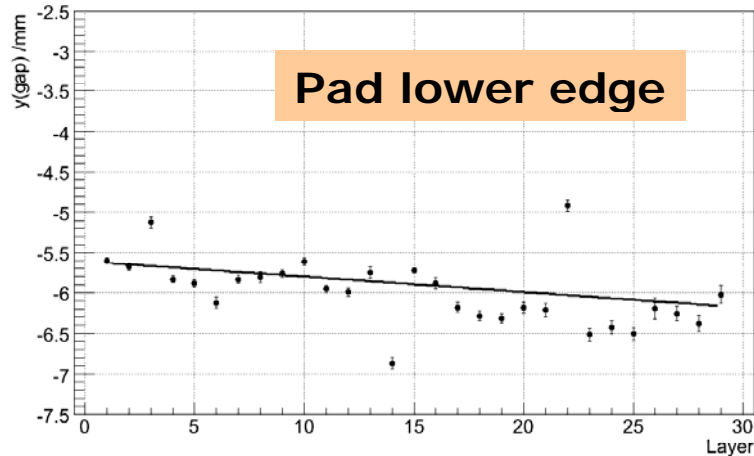
- Stagger of wafers in x is clearly seen
- Tilt of ECAL (or displacement of stacks) is seen. $\sim 5-10$ mrad?
- Apparent pad width shows imprint of the stagger structure. So less clear how to use this information.
- Probably drift velocity correction in x should be $\sim 1.12 \pm 0.02$. Consistent with old method.

Run 330467 "(0,+3)" nominal



One well populated pad - adjoins interwafer gap; hence effective pad width not known.

330467 y



- Fits are less stable. Reflect ununderstood structures seen in previous page
- Apparent pad width ~ 13.3 mm (compared to ~ 12 mm for 330436).
- But what should it be? How well are inter-wafer gaps controlled anyway?
- Probably need to study high statistics muon runs.